Date Created : **2007/05/10**
Date Issued On : **2007/06/26**
PCN# : **Q2071909**

DESIGN/PROCESS CHANGE NOTIFICATION -- FINAL

This is to inform you that a design and/or process change will be made to the following product(s). This notification is for your information and concurrence.

If you require data or samples to qualify this change, please contact **Fairchild Semiconductor within 30 days of receipt of this notification.**

Updated process quality documentation, such as FMEAs and Control Plans, are available for viewing upon request.

If you have any questions concerning this change, please contact:

Technical Contact:
Name: LEE, JEONGSOO
E-mail: JEONGSOO.LEE@fairchildsemi.com
Phone: 82-32-680-1311

PCN Originator:
Name: LEE, JEONGSOO
E-mail: JEONGSOO.LEE@fairchildsemi.com
Phone: 82-32-680-1311

Implementation of change:
Expected 1st Device Shipment Date: 2007/08/12

Earliest Year/Work Week of Changed Product: H33

Change Type Description: Data Book Specifications

Description of Change (From): There are some items which will be corrected from gFS: 15S(Typ)// td(on): 7.2ns(Typ), 25(max)// tr: 68ns(typ), 146ns(max)// td(off): 77ns(typ), 164ns(max)// tf: 93ns(typ), 196ns(max)// trr: 62ns(typ)// Qrr: 150nC(typ)

Description of Change (To): to gFS: 32S(Typ)// td(on): 39ns(Typ), 88(max)// tr: 181ns(typ), 372ns(max)// td(off): 183ns(typ), 376ns(max)// tf: 82ns(typ), 173ns(max)// trr: 80ns(typ)// Qrr: 193nC(typ)

Reason for Change : To correct the limiation of some items because we had tested miss target samples of FDP75N08.

Qual/REL Plan Numbers : Q20050324

FDP75N08 vehicle lot for new product design has successfully passed 1000hours and met the conditions for release as specified in the qualification plan.

Qualification :

Passed 1000hours and met the conditions for release as specified in the qualification plan

Results/Discussion

Test: (Autoclave)			
Lot	Device	96-HOURS	Failure Code
Q20050324AAACLV	FDP50N06	0/77	

Test: (High Temperature Gate Bias)					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20050324AAHTGB	FDP50N06	0/77			
			0/77		
				0/77	

Test: (High Temperature Reverse Bias)					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20050324AAHTRB		0/77			
			0/77		
				0/77	

Test: (Human Body Model ESD)			
Lot	Device	Results	Failure Code
Q20050324AAHBM	FDP50N06	0/6	

Test: (Machine Model ESD)			
Lot	Device	Results	Failure Code
Q20050324AAMM	FDP50N06	0/6	

Test: (Temperature Humidity Biased Test)					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20050324AATHBT		0/77			
			0/77		
				0/77	

Test: -65C, 150C (Temperature Cycle)				
Lot	Device	200-CYCLES	500-CYCLES	Failure Code
Q20050324AATMCL1	FDP50N06	0/77		
Q20050324AATMCL1	FDP50N06		0/77	

Product Id Description : There is UniFET product, FDP75N08.

Affected FSIDs :

FDP75N08		